



# WAN Tester II

- Tests asynchronous, synchronous, DDS, T-1, fractional T-1, E-1 and fractional E-1, T-3 and E-3 facilities and equipment
- V.35, RS232, RS422/RS530, X.21, HSSI, DDS, T-1, E-1, T-3 and E-3 interfaces
- Data rates from 50 bps to 50 Mbps
- Displays G.821 performance measurements
- Front panel, Windows GUI or terminal Command Line Interface control
- AC or battery power

The Telinc WAN Tester II is a sophisticated bit error rate tester in a compact, hand held package. It can test a wide variety of communications facilities and equipment including DDS, T-1, fractional T-1, E-1, fractional E-1, T-3 and E-3 NTUs, multiplexers, CSU/DSUs, T-1 CSUs, DTUs and TIUs. It includes a speaker to listen to voice in a DS0. It is supplied with changeable nickel metal hydride batteries and a built-in charger.

## T-1 and E-1 Testing

In the T-1 and E-1 modes, the Tester displays bit errors, transmit and receive frequency, test seconds, bit error rate and G.821 performance measurements (errored seconds, severely errored seconds, degraded minutes and available and unavailable times). A variety of test patterns can be inserted in all or selected DS0s/timeslots, continuous or non-contiguous, making the Tester ideal for fractional T-1 or E-1 testing. In the T-1 mode, it also displays RX level in db and volts.

## T-3 and E-3 Testing

The WAN Tester II can test T-3 and E-3 networks and CSUs. It performs G.821 measurements and displays bit errors, bit error rate, frequency and more.

## Async and Sync Testing

In the async and sync test mode, the Tester generates test data in a choice of patterns and formats. The user can select from twenty-eight async and seventy-eight sync test speeds. The Tester displays bit errors, bit error rate and total test seconds. In the async mode, it displays characters received, character errors and errored seconds. In the sync mode, it also displays TX frequency, RX frequency, CTS delay and G.821 measurements.

## DDS Testing

The Tester also includes a DDS analyzer. It can operate at speeds from 2400 to 72,000 bps in normal and Secondary Channel modes. It can simulate a CSU/DSU to test networks or a network to test CSU/DSUs.

## Easy to use

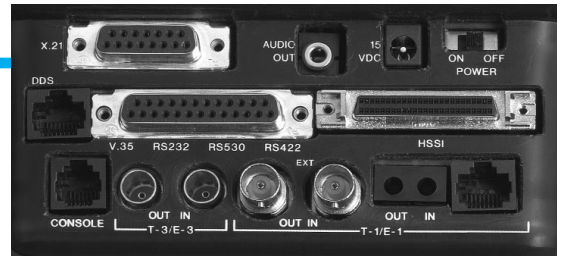
The WAN Tester II can be controlled from the front panel or from a local or remote terminal. It includes a two-line LCD display and nineteen LED indicators that show selected mode, test and operating parameters. Parameters are selected by scrolling through values stored in the Tester.

# WAN Tester II

## Specifications

### ASYN

**Speeds:** 50 to 115,000 bps  
**Displays:** Character Errors, Characters Received, Total Test Seconds and Errored Seconds  
**LEDS:** Pattern Lock, Pattern Recovered, TXD, RXD, RTS, CTS, DSR, CD, and DTR  
**Patterns:** 2<sup>9</sup> (511), 2<sup>11</sup> (2047), Binary, Fox Test, Mark and Space  
**Loops:** SelfTest  
**Interfaces:** V.35, RS530, RS422 and RS232 Physical: DB 25 pin Female



The Telinc Tester is supplied complete with all the interfaces listed.

### SYNC

**Speeds:** 1,200 to 50,000,000 bps  
**Displays:** Bit Errors, Bit Error Rate, Test Secs, Errored Secs, Severely Errored Secs, Degraded Mins, Available, Unavailable, RX Freq, TX Freq, Bits Received, RTS Time, Round Trip Delay  
**LEDS:** Pattern Lock, Pattern Recovered, Transmit Data, Receive Data, RTS (C), CTS, DSR, CD (J), DTR, TXC, RXC (S), and External TXC  
**Patterns:** 2<sup>9</sup> (511), 2<sup>11</sup> (2047), 2<sup>15</sup>, ITU 2<sup>15</sup>, QRSS, 2<sup>20</sup>, ITU 2<sup>20</sup>, 2<sup>23</sup>, ITU 2<sup>23</sup>, 1 of 8, 3 of 24, Alt, Mark, Space, Round Trip Delay and User 3 - 32  
**Loops:** SelfTest and V.54  
**Interfaces:** V.35/DB25, RS530/DB25, RS422/DB25, RS232/DB25, X.21/DB15 and HSSI/50 pin

### DDS

**Speeds:** 2,400 to 72,000 bps  
**Displays:** Bit Errors, Bit Error Rate, Test Secs, Errored Secs, , Secondary Errors, Severely Errored Secs, Degraded Mins, Available, Unavailable, RX Freq, TX Freq, Bits, RX Level dB, Simplex Current, Round Trip Delay and RLOS Secs  
**LEDS:** Pattern Lock, Pattern Recovered, CMI (IDLE), All 1s, All 0s, RLOS, OOF, OOS, CSU Loop, DSU Loop and V.54 Loop  
**Patterns:** 2<sup>9</sup> (511), 2<sup>11</sup> (2047), 2<sup>15</sup>, QRSS, 1 of 8, 3 of 24, Alt, Mark, Space, DDS1, DDS2, DDS3, DDS4, Round Trip Delay and User 3 - 32  
**Loops:** SelfTest, CSU Loop, DSU Loop and V.54 Loop  
**Interfaces:** Four wire, BiPolar Physical: RJ48S

### T-1

**Speed:** 1,544,000 bps  
**Displays:** Bit Errors, Bit Error Rate, Test Secs, Errored Secs, Severely Errored Secs, Degraded Mins, Available, Unavailable, RX Freq, TX Freq, Signalling Bits, Density Errs, Frame Errs, CRC Err, BPV Err, RX Level Volts & dB, Slips, Round Trip Delay  
**LEDS:** Pattern Lock, Pattern Recovered, Frame Lock, AIS (Blue), RLOS, CRC Err, BPV, D4, ESF, AMI, B8ZS and Yellow  
**Patterns:** 2<sup>9</sup> (511), 2<sup>11</sup> (2047), 2<sup>15</sup>, ITU 2<sup>15</sup>, QRSS, 2<sup>20</sup>, ITU 2<sup>20</sup>, 2<sup>23</sup>, ITU 2<sup>23</sup>, 1 of 8, 3 of 24, T-1 DALY, T-1 DALY UF, 55 Octet, 55 Octet UF, Alt, Mark, Space , Digimwatt, User 3 - 32, Round Trip Delay, DDS OCU Loop, DDS CSU Loop and DDS DSU Loop  
**Loops:** SelfTest, ATT Loop U/D, ANSI Loop U/D, ATT Payload, ANSI Payload, Smart Jack 1 & 2 (Framed & Unframed) and V.54  
**Interfaces:** DS1 BiPolar, 110 Ohm, AMI/B8ZS Coding Physical: RJ48C and Dual Bantam

### E-1

**Speed:** 2,048,000 bps  
**Displays:** Bit Errors, Bit Error Rate, Test Secs, Errored Secs, Severely Errored Secs, Degraded Mins, Available, Unavailable, RX Freq, TX Freq, CRC Errs, BPV Errs and Frame Errs  
**LEDS:** Pattern Lock, Pattern Recovered, Frame Lock, AIS (Blue), RLOS, CRC Err, BPV, DMFA and RRA  
**Patterns:** 2<sup>9</sup> (511), 2<sup>11</sup> (2047), 2<sup>15</sup>, ITU 2<sup>15</sup>, QRSS, 2<sup>20</sup>, ITU 2<sup>20</sup>, 2<sup>23</sup>, ITU 2<sup>23</sup>, 1 of 8, 3 of 24, Alt, Mark, Space, Digimwatt and User 3 - 32  
**Loops:** SelfTest and V.54  
**Interfaces:** G.703/704, 75 & 120 Ohm, HDB3 Coding Physical: Dual Bantam, Dual BNC and RJ48C

### T-3

**Speed:** 44,736,000 bps  
**Displays:** Bit Errors, Bit Error Rate, Test Secs, Errored Secs, Severely Errored Secs, Degraded Mins, Available, Unavailable, RX Freq, TX Freq, P-Bit Errs, C-Bit Errs, T3 & T2 Frame Errs, LCV Err, FEBE Err, Excessive 0s and LOS Secs  
**LEDS:** Pattern Lock, Pattern Recovered, Frame Lock, AIS (Blue), RLOS, LOF, LCV, FEBE, Yellow, M13 and C-Bit  
**Patterns:** 2<sup>9</sup> (511), 2<sup>11</sup> (2047), 2<sup>15</sup>, ITU 2<sup>15</sup>, QRSS, 2<sup>20</sup>, ITU 2<sup>20</sup>, 2<sup>23</sup>, ITU 2<sup>23</sup>, 1111, IDLE 1100, AIS 1010, 0000, 1 of 8 and User 3 - 32  
**Loops:** SelfTest and CSU  
**Interfaces:** DS3 BiPolar, 75 Ohm Physical: Dual Mini WECO 560A

### E-3

**Speed:** 34,368,000 bps  
**Displays:** Bit Errors, Bit Error Rate, Test Secs, Errored Secs, Severely Errored Secs, Degraded Mins, Available, Unavailable, RX Freq, TX Freq, LCVs, LOS Secs and Frame Errs  
**LEDS:** Pattern Lock, Pattern Recovered, Frame Lock, AIS (Blue), RLOS, LOF, BPV, and RAI  
**Patterns:** 2<sup>9</sup> (511), 2<sup>11</sup> (2047), 2<sup>15</sup>, ITU 2<sup>15</sup>, QRSS, 2<sup>20</sup>, ITU 2<sup>20</sup>, 2<sup>23</sup>, ITU 2<sup>23</sup>, 1 of 8, Alt, Mark, Space and User 3 - 32  
**Loops:** SelfTest and LINE  
**Interfaces:** G.703/751, 75 Ohm, HDB3 Coding Physical: Dual Mini WECO 560A

**Mechanical:** The WAN Tester II measures 8.75" (22.2 cm) H x 7.5" (19.1 cm) W x 4" (10.2 cm) D and weighs 4.4 lbs (1.81 kg)

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